

PETRA III Workshop: HighRes and RSD Beamlines

Thursday 27 September 2007

High Resolution and Diffraction Beamline - Bldg. 25f, room 456 (10:30 - 17:20)

time	[id] title	presenter
10:30	[19] A liquid diffractometer for PETRA III	MURPHY, Bridget
11:10	[20] Phase behavior and design of polyfluorenes	KNAAPILA, Matti
11:50	Lunch	
13:05	[21] Investigations of the structure and morphology of ultrathin films on Si by x-ray diffraction and reflection	DEITER, Carsten
13:45	[22] Organic thin films and bio-interfaces	NICKEL, Bert
14:25	[23] Strain determination at semiconductor lateral surface gratings using high resolution x-ray diffraction	PIETSCH, Ullrich
15:05	Coffee break	
15:20	[24] Requirement of a diffraction beamline for the study of surfaces interfaces and thin films in material science	CAPITAN, Maria
16:00	[25] Synchrotron x-ray diffraction and ferroelasticity in thin films with periodic nano domains	NOHEDA, Beatriz
16:40	[26] X-ray diffraction and scattering beamline ID32 at the ESRF	ZEGENHAGEN, Jörg